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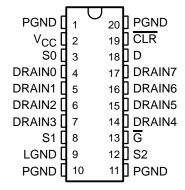
- Low r<sub>DS(on)</sub> . . . 1.3 Ω Typical
- Avalanche Energy . . . 75 mJ
- Eight Power DMOS Transistor Outputs of 250-mA Continuous Current
- 1.5-A Pulsed Current Per Output
- Output Clamp Voltage at 45 V
- Four Distinct Function Modes
- Low Power Consumption

## description

This power logic 8-bit addressable latch controls open-drain DMOS transistor outputs and is designed for general-purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and decoders or demultiplexers. This is a multifunctional device capable of storing single-line data in eight addressable latches with 3-to-8 decoding or demultiplexing mode active-low DMOS outputs.

Four distinct modes of operation are selectable by controlling the clear  $(\overline{CLR})$  and enable  $(\overline{G})$  inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in (D) terminal is written into the addressed latch. The addressed DMOS transistor output inverts the data input with all unaddressed DMOS-transistor outputs remaining in their previous states. In the memory mode, all DMOS-transistor outputs remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latch, enable  $\overline{G}$  should be held high (inactive) while the address lines are changing. In the 3-to-8 decoding

#### DW OR N PACKAGE (TOP VIEW)



#### **FUNCTION TABLE**

INPUTS		S	OUTPUT OF	EACH	FUNCTION
CLR	G	D	ADDRESSED DRAIN	OTHER DRAIN	FUNCTION
H H	L L	H L	L H	Q <sub>io</sub> Q <sub>io</sub>	Addressable Latch
Н	Н	Χ	Q <sub>io</sub>	Q <sub>io</sub>	Memory
L L	L L	H L	L H	H H	8-Line Demultiplexer
L	Н	X	Н	Н	Clear

#### **LATCH SELECTION TABLE**

S	ELE	CT IN	DRAIN	
	S2	S1	S0	ADDRESSED
	L	L	L	0
	L	L	Н	1
	L	Н	L	2
	L	Н	Н	3
	Н	L	L	4
	Н	L	Н	5
	Н	Н	L	6
	Н	Н	Н	7

or demultiplexing mode, the addressed output is inverted with respect to the D input and all other outputs are high. In the clear mode, all outputs are high and unaffected by the address and data inputs.

Separate power and logic level ground pins are provided to facilitate maximum system flexibility. Pins 1, 10, 11, and 20 are internally connected, and each pin must be externally connected to the power system ground in order to minimize parasitic inductance. A single-point connection between pin 9, logic ground (LGND), and pins 1, 10, 11, and 20, power ground (PGND) must be externally made in a manner that reduces crosstalk between the logic and load circuits.

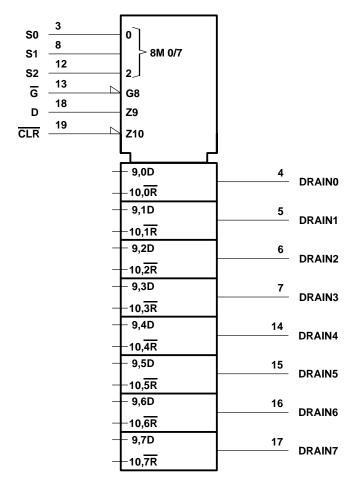
The TPIC6259 is characterized for operation over the operating case temperature range of -40°C to 125°C.



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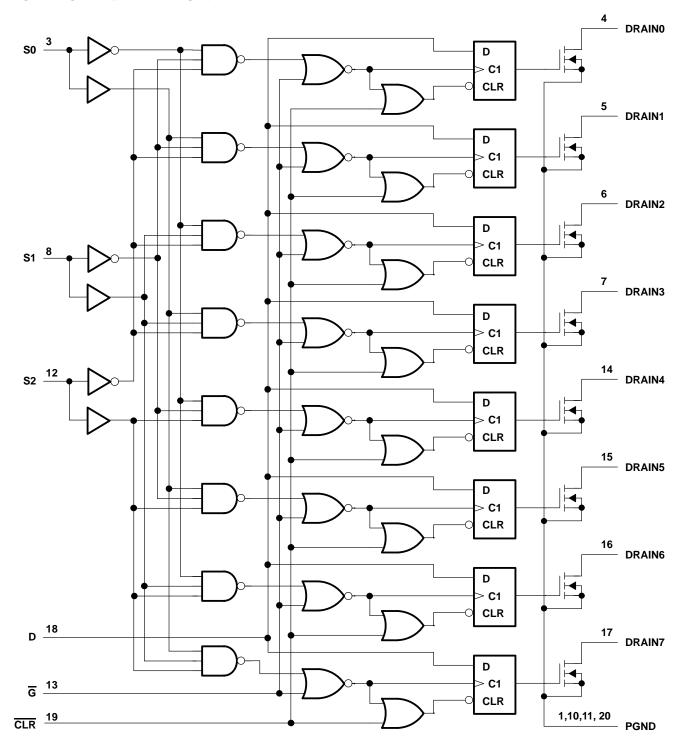


## logic symbol†



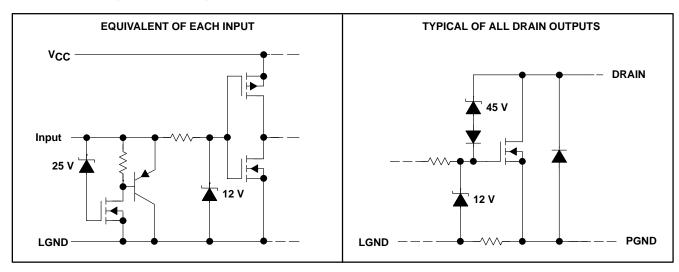
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



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## schematic of inputs and outputs



# absolute maximum ratings over the recommended operating case temperature range (unless otherwise noted) $^{\dagger}$

Logic supply voltage, V <sub>CC</sub> (see Note 1)	
Logic input voltage range, V <sub>I</sub>	
Power DMOS drain-to-source voltage, V <sub>DS</sub> (see Note 2)	45 V
Continuous source-drain diode anode current	1 A
Pulsed source-drain diode anode current	2 A
Pulsed drain current, each output, all outputs on, $I_{Dn}$ , $T_A = 25^{\circ}C$ (see Note 3)	750 mA
Continuous drain current, each output, all outputs on, I <sub>Dn.</sub> T <sub>A</sub> = 25°C	250 mA
Peak drain current single output, I <sub>DM</sub> , T <sub>A</sub> = 25°C (see Note 3)	
Single-pulse avalanche energy, E <sub>AS</sub> (see Note 4)	75 mJ
Avalanche current, I <sub>AS</sub> (see Note 4)	1 A
Continuous total power dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T <sub>J</sub>	40°C to 150°C
Storage temperature range, T <sub>stq</sub>	
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to LGND and PGND.
  - 2. Each power DMOS source is internally connected to PGND.
  - 3. Pulse duration  $\leq$  100  $\mu$ s, duty cycle  $\leq$  2%
  - 4. DRAIN supply voltage = 15 V, starting junction temperature,  $(T_{JS}) = 25^{\circ}C$ , L = 100 mH,  $I_{AS} = 1$  A (see Figure 4).

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
N	1150 mW	9.2 mW/°C	230 mW



# recommended operating conditions over recommended operating temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Logic supply voltage, V <sub>CC</sub>	4.5	5.5	V
High-level input voltage, VIH	0.85 V <sub>C</sub> C		V
Low-level input voltage, V <sub>IL</sub>		0.15 V <sub>CC</sub>	V
Pulsed drain output current, T <sub>C</sub> = 25°C, V <sub>CC</sub> = 5 V (see Notes 3 and 5)	-1.8	1.5	Α
Setup time, D high before $\overline{G} \uparrow$ , t <sub>SU</sub> (see Figure 2)	10		ns
Hold time, D high after $\overline{G}\uparrow$ , t <sub>h</sub> (see Figure 2)	5		ns
Pulse duration, t <sub>W</sub> (see Figure 2)	15		ns
Operating case temperature, T <sub>C</sub>	-40	125	°C

# electrical characteristics, $V_{CC}$ = 5 V, $T_{C}$ = 25°C (unless otherwise noted)

	PARAMETER	•	TEST CONDITI	ONS	MIN	TYP	MAX	UNIT
V <sub>(BR)DSX</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA			45			V
$V_{SD}$	Source-drain diode forward voltage	$I_F = 250 \text{ mA},$	See Note 3			0.85	1	V
lн	High-level input current	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$				1	μΑ
I <sub>Ι</sub> L	Low-level input current	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 0				-1	μΑ
ICC	Logic supply current	I <sub>O</sub> = 0,	All inputs low			15	100	μΑ
IN	Nominal current	V <sub>DS(on)</sub> = 0.5 V <sub>s</sub> See Notes 5, 6, a	$I_N = I_D$ , and 7	T <sub>C</sub> = 85°C,		250		mA
la ov	Off-state drain current	V <sub>DS</sub> = 40 V				0.05	1	
IDSX	On-state drain current	$V_{DS} = 40 \text{ V},$	T <sub>C</sub> = 125°C			0.15	5	μΑ
		$I_D = 250 \text{ mA},$	V <sub>CC</sub> = 4.5 V			1.3	2	
rDS(on)	Static drain-source on-state resistance	I <sub>D</sub> = 250 mA, V <sub>CC</sub> = 4.5 V	$T_{C} = 125^{\circ}C,$	See Notes 5 and 6 and Figures 8 and 9		2	3.2	Ω
		I <sub>D</sub> = 500 mA,	V <sub>CC</sub> = 4.5 V			1.3	2	

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_{C} = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPLH	Propagation delay time, low-to-high-level output from D			625		ns
tPHL	Propagation delay time, high-to-low-level output from D	$C_L = 30 \text{ pF}, \qquad I_D = 250 \text{ mA},$		140		ns
t <sub>r</sub>	Rise time, drain output	See Figures 1, 2, and 10		650		ns
t <sub>f</sub>	Fall time, drain output			400		ns
ta	Reverse-recovery-current rise time	$I_F = 250 \text{ mA},   di/dt = 20 \text{ A/}\mu\text{s},$		100		200
t <sub>rr</sub>	Reverse-recovery time	See Notes 5 and 6 and Figure 3		300		ns

NOTES: 3. Pulse duration  $\leq$  100  $\mu$ s, duty cycle  $\leq$  2%

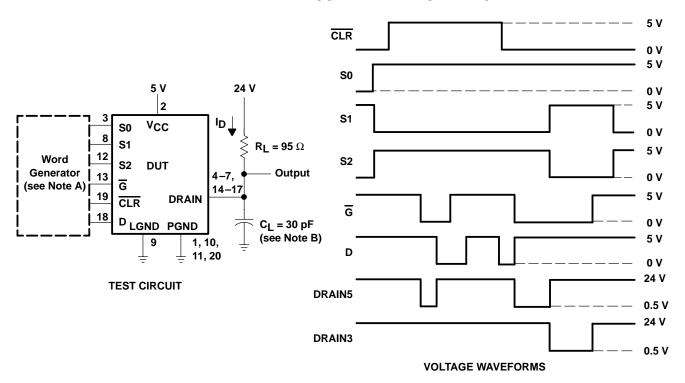
- 5. Technique should limit  $T_J T_C$  to 10°C maximum.
- 6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.
- 7. Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at T<sub>C</sub> = 85°C.

#### thermal resistance

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT	
_	Thermal registeres investiga to embient	DW package	All 9 outputs with equal power		111	°C/W
$R_{\theta JA}$	Thermal resistance junction-to-ambient	N package	All 8 outputs with equal power		108	-0/00



### PARAMETER MEASUREMENT INFORMATION



**Figure 1. Typical Operation Mode** 

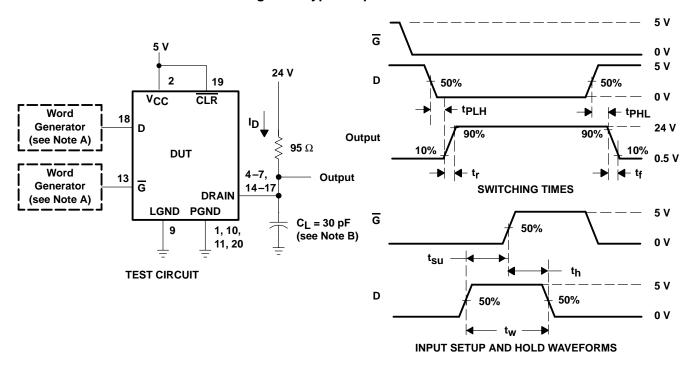


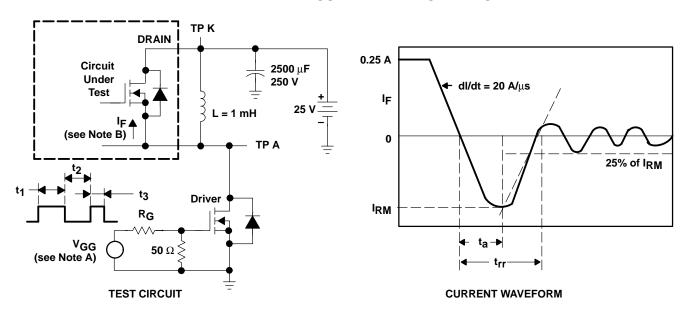
Figure 2. Test Circuit, Switching Times, and Voltage Waveforms

NOTES: A. The word generator has the following characteristics:  $t_{\Gamma} \le 10$  ns,  $t_{W} = 300$  ns, pulsed repetition rate (PRR) = 5 kHz,  $Z_O = 50 \Omega$ .

B. C<sub>L</sub> includes probe and jig capacitance.

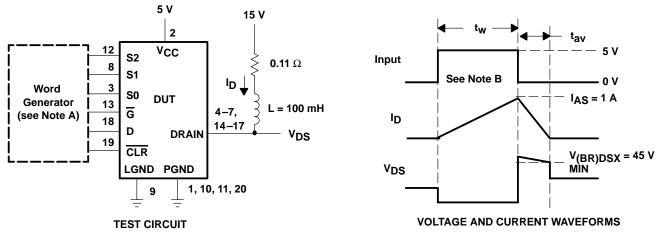


#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The VGG amplitude and RG are adjusted for di/dt = 20 A/ $\mu$ s. A VGG double-pulse train is used to set IF = 0.25 A, where  $t_1$  = 10  $\mu$ s,  $t_2$  = 7  $\mu$ s, and  $t_3$  = 3  $\mu$ s.
  - B. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.

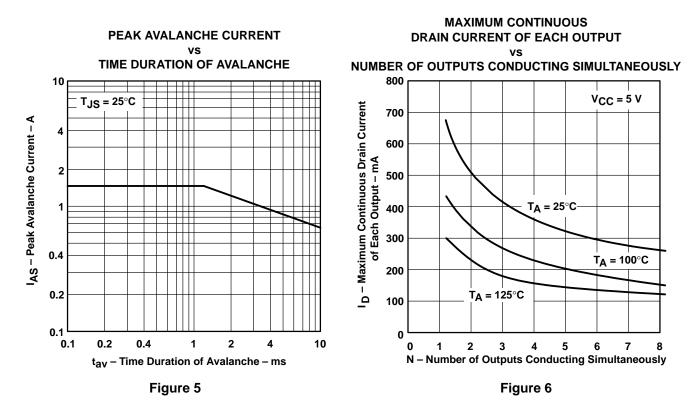
Figure 3. Reverse-Recovery-Current Test Circuit and Waveforms of Source-Drain Diode



- NOTES: A. The pulse generator has the following characteristics:  $t_r \le 10$  ns,  $t_f \le 10$  ns,  $t_O = 50$   $\Omega$ .
  - B. Input pulse duration,  $t_W$ , is increased until peak current  $I_{AS} = 1$  A. Energy test level is defined as  $E_{AS} = I_{AS} \times V_{(BR)DSX} \times t_{av}/2 = 75$  mJ.

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

#### TYPICAL CHARACTERISTICS



### MAXIMUM PEAK DRAIN CURRENT OF EACH OUTPUT vs

#### NUMBER OF OUTPUTS CONDUCTING SIMULTANEOUSLY

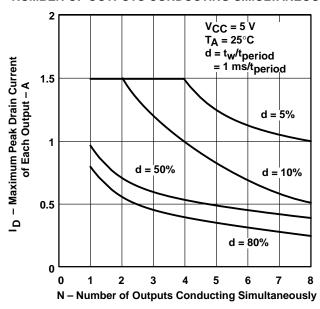
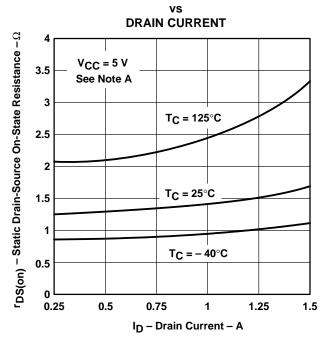


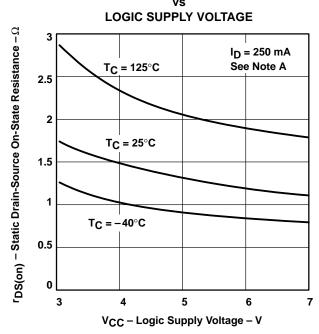
Figure 7

### TYPICAL CHARACTERISTICS

## STATIC DRAIN-SOURCE ON-STATE RESISTANCE



# STATIC DRAIN-SOURCE ON-STATE RESISTANCE



#### Figure 9 Figure 8

**SWITCHING TIME** vs

## FREE-AIR TEMPERATURE 700 tr 600 <sup>t</sup>PLH $I_D = 250 \text{ mA}$ 500 See Note A tf

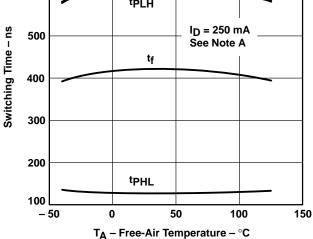


Figure 10

NOTE A: Technique should limit T<sub>J</sub> – T<sub>C</sub> to 10°C maximum.



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